

Notice of References Cited	Application/Control No. 10/565,564		Applicant(s)/Patent Under Reexamination SETHI ET AL.	
	Examiner John Kreck		Art Unit 3672	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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	N	JP 2002136961 A	05-2002	Japan	TANO et al.	B09C 01/02
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NON-PATENT DOCUMENTS

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